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(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Butt et al.

Application No.: Not Yet Assigned

Group Art Unit: N/A

Filed: Concurrently Herewith

Examiner: Not Yet Assigned

For: OPTICAL MEASUREMENT OF DEVICE FEATURES USING INTERFEROMETRIC

ILLUMINATION

MS Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

It is respectfully requested that the references listed on the enclosed form be made of record and considered with respect to the above-referenced U.S. patent application. A copy of each non-U.S. patent reference is enclosed. Submission of the present Information Disclosure Statement should not be taken as an admission that the cited references are legally available prior art or that the same are pertinent or material.

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Dated: February 3, 2004

Respectfully submitted,

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PTO/SB/08a/b (08-03)
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	Salute for form 1440/VD/1			Application Number	Not Yet Assigned	
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S	TATEMENT	BY /	APPLICANT	First Named Inventor	Shahid Butt	
				Art Unit	N/A	
	(Use as many st	heets as	necessary)	Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	03P51158US/INTECH 3.0-100	

	U.S. PATENT DOCUMENTS						
	Cite No.1	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
Examiner Initials*		Number-Kind Code ² (if known)	MM-DD-YYYY	Applicant of Cited Document			
	AA	US-6,552,795-B1	04-22-2003	Bewersdorf			
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Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		EP 0 491 289 B1	12-12-1991	Hell		X

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NON PATENT LITERATURE DOCUMENTS						
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	CA	Zecchino, et al., "High Speed Surface Measurement with Lateral Scanning White Light Interferometry", Veeco Instruments, Inc., 2002				

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